



PATENT *IFW*

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

BOYD et al.

Application No. 10/606,022

Filed: June 24, 2003

For: SYSTEM AND METHOD FOR
INTEGRATING IN-SITU METROLOGY WITHIN
A WAFER PROCESS

) Group Art Unit: 1746
)
) Examiner: Unassigned
)
) Atty. Docket No.: LAM2P425
)
) Date: February 1, 2006

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450 Alexandria, VA 22313-1450 on **February 1, 2006**.

Signed: *Cynthia Dawn*
Cynthia Dawn

INFORMATION DISCLOSURE STATEMENT UNDER 37 CFR §§1.97(e)

Commissioner for Patents
P. O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

The references listed in the attached PTO Form 1449 may be material to examination of the above-identified patent application. Applicants submit the foreign patent document and non-patent literature reference in compliance with their duty of disclosure pursuant to 37 CFR §§ 1.56 and 1.97. The Examiner is requested to consider these references and the U. S. patent document to acknowledge such consideration by initialing the attached PTO Form 1449 at the appropriate locations.

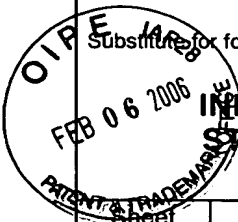
Applicants state that each item of information contained in the information disclosure statement was first cited in any communication from a foreign patent office in a counterpart foreign application. For the Examiner's use and information, a copy of the International Search Report in the corresponding international application is attached.

This IDS is believed to be filed before the mailing date of a first Office Action. Accordingly, it is believed that no fees are due in connection with the filing of this IDS. However, if it is determined that any fees are due, then the Commissioner is hereby authorized to charge such fees to Deposit Account 50-0805 (Order No. LAM2P425).

Respectfully submitted,
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 Substitution for form 1449/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/606,022
				Filing Date	June 24, 2003
				First Named Inventor	Boyd
				Art Unit	1746
				Examiner Name	Unassigned
Sheet 1 of 1	Attorney Docket Number	LAM2P425			

U.S. Patent Documents

Examiner Initials	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			
	A	2004/136494	07/15/2004	Joeri, et al.	
	B				
	C				
	D				
	E				
	F				
	G				
	H				

Foreign Patent Documents

Examiner Initial	Cite No. ¹	Foreign Patent Document No.	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, where Relevant Passages or Relevant Figures Appear	T ⁶
		Country Code ³ -Number ⁴ -Kind Code ⁵ (if known)				
	I	WO 99/49504	EP	Nikon Corp.		<input type="checkbox"/>
	J	EP 1 489 461	EP	ASML Netherlands B.V.		<input type="checkbox"/>
	K	EP 1 489 462	EP	ASML Netherlands B.V.		<input type="checkbox"/>
	L					<input type="checkbox"/>
	M					<input type="checkbox"/>

Non Patent Literature Documents

Examiner Initial	Cite No.	Include name of author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published
	N	International Search Report
	O	Owa, et al., "Immersion Lithography; Its Potential Performance and Issues," <i>Proceedings of the SPIE, SPIE, Bellingham, VA</i> , Vol. 5040, No. 1, February 28, 2003, pp. 724-33, XP002294500, ISSN: 0277-786X

Examiner Signature		Date Considered	
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Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language translation is attached.